

## SINGLE BUS BUFFER (3-STATE)

- HIGH SPEED:  $t_{PD} = 3.8 \text{ ns}$  (TYP.) at  $V_{CC} = 5\text{V}$
- LOW POWER DISSIPATION:  
 $I_{CC} = 1 \mu\text{A}$  (MAX.) at  $T_A = 25^\circ\text{C}$
- HIGH NOISE IMMUNITY:  
 $V_{NIH} = V_{NIL} = 28\%$   $V_{CC}$  (MIN.)
- POWER DOWN PROTECTION ON INPUTS
- SYMMETRICAL OUTPUT IMPEDANCE:  
 $|I_{OH}| = I_{OL} = 8 \text{ mA}$  (MIN)
- BALANCED PROPAGATION DELAYS:  
 $t_{PLH} \approx t_{PHL}$
- OPERATING VOLTAGE RANGE:  
 $V_{CC}$  (OPR) = 2V to 5.5V
- IMPROVED LATCH-UP IMMUNITY

### DESCRIPTION

The 74V1G125 is an advanced high-speed CMOS SINGLE BUS BUFFER fabricated with sub-micron silicon gate and double-layer metal wiring C<sup>2</sup>MOS technology. It has similar high speed performance of equivalent Bipolar Schottky TTL combined with true CMOS low power dissipation.

### PRELIMINARY DATA



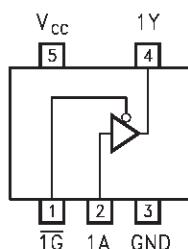
**S**  
(SOT23-5L)

**ORDER CODE:**  
74V1G125S

3-STATE control input  $\overline{G}$  has to be set high to place the output into the high impedance state. Power down protection is provided on all inputs and 0 to 7V can be accepted on inputs with no regard to the supply voltage. This device can be used to interface 5V to 3V.

All inputs and outputs are equipped with protection circuits against static discharge, giving them 2KV ESD immunity and transient excess voltage.

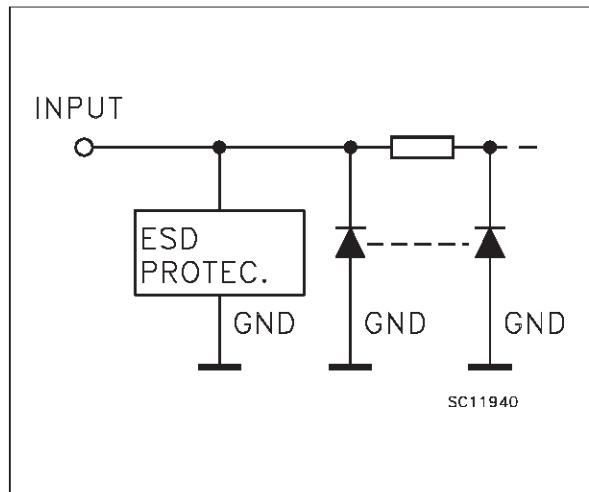
### PIN CONNECTION AND IEC LOGIC SYMBOLS



SC12310



## INPUT EQUIVALENT CIRCUIT



## PIN DESCRIPTION

PIN No	SYMBOL	NAME AND FUNCTION
1	1 $\bar{G}$	Output Enable Input
2	1A	Data Input
4	1Y	Data Output
3	GND	Ground (0V)
5	V <sub>CC</sub>	Positive Supply Voltage

## TRUTH TABLE

A	$\bar{G}$	Y
X	H	Z
L	L	L
H	L	H

X: "H" or "L" Z: High Impedance

## ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V <sub>CC</sub>	Supply Voltage	-0.5 to +7.0	V
V <sub>I</sub>	DC Input Voltage	-0.5 to +7.0	V
V <sub>O</sub>	DC Output Voltage	-0.5 to V <sub>CC</sub> + 0.5	V
I <sub>IK</sub>	DC Input Diode Current	- 20	mA
I <sub>OK</sub>	DC Output Diode Current	$\pm$ 20	mA
I <sub>O</sub>	DC Output Current	$\pm$ 25	mA
I <sub>CC</sub> or I <sub>GND</sub>	DC V <sub>CC</sub> or Ground Current	$\pm$ 50	mA
T <sub>stg</sub>	Storage Temperature	-65 to +150	°C
T <sub>L</sub>	Lead Temperature (10 sec)	260	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these condition is not implied.

## RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Value	Unit
V <sub>CC</sub>	Supply Voltage	2.0 to 5.5	V
V <sub>I</sub>	Input Voltage	0 to 5.5	V
V <sub>O</sub>	Output Voltage	0 to V <sub>CC</sub>	V
T <sub>op</sub>	Operating Temperature	-40 to +85	°C
dt/dv	Input Rise and Fall Time (see note 1) (V <sub>CC</sub> = 3.3 ± 0.3V) (V <sub>CC</sub> = 5.0 ± 0.5V)	0 to 100 0 to 20	ns/V ns/V

1) V<sub>IN</sub> from 30% to 70% of V<sub>CC</sub>

## DC SPECIFICATIONS

Symbol	Parameter	Test Conditions		Value					Unit	
		V <sub>CC</sub> (V)		T <sub>A</sub> = 25 °C			-40 to 85 °C			
				Min.	Typ.	Max.	Min.	Max.		
V <sub>IH</sub>	High Level Input Voltage	2.0		1.5			1.5		V	
		3.0 to 5.5		0.7V <sub>CC</sub>			0.7V <sub>CC</sub>			
V <sub>IL</sub>	Low Level Input Voltage	2.0				0.5		0.5	V	
		3.0 to 5.5				0.3V <sub>CC</sub>		0.3V <sub>CC</sub>		
V <sub>OH</sub>	High Level Output Voltage	2.0	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>O</sub> =-50 μA	1.9	2.0		1.9	V	
		3.0		I <sub>O</sub> =-50 μA	2.9	3.0		2.9		
		4.5		I <sub>O</sub> =-50 μA	4.4	4.5		4.4		
		3.0		I <sub>O</sub> =-4 mA	2.58			2.48		
		4.5		I <sub>O</sub> =-8 mA	3.94			3.8		
V <sub>OL</sub>	Low Level Output Voltage	2.0	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>O</sub> =50 μA		0.0	0.1		V	
		3.0		I <sub>O</sub> =50 μA		0.0	0.1			
		4.5		I <sub>O</sub> =50 μA		0.0	0.1			
		3.0		I <sub>O</sub> =4 mA			0.36	0.44		
		4.5		I <sub>O</sub> =8 mA			0.36	0.44		
I <sub>OZ</sub>	3 State Output Leakage Current	5.5	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub> V <sub>O</sub> = V <sub>CC</sub> or GND				±0.25		±2.5 μA	
I <sub>I</sub>	Input Leakage Current	0 to 5.5	V <sub>I</sub> = 5.5V or GND				±0.1		±1.0 μA	
I <sub>CC</sub>	Quiescent Supply Current	5.5	V <sub>I</sub> = V <sub>CC</sub> or GND			1		10	μA	

AC ELECTRICAL CHARACTERISTICS (Input t<sub>r</sub> = t<sub>f</sub> = 3 ns)

Symbol	Parameter	Test Condition		Value					Unit	
		V <sub>CC</sub> (V)		T <sub>A</sub> = 25 °C			-40 to 85 °C			
				Min.	Typ.	Max.	Min.	Max.		
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay Time	3.3 <sup>(*)</sup>	C <sub>L</sub> = 15 pF		5.6	8.0	1.0	9.5	ns	
		3.3 <sup>(*)</sup>	C <sub>L</sub> = 50 pF		8.1	11.5	1.0	13.0		
		5.0 <sup>(**)</sup>	C <sub>L</sub> = 15 pF		3.8	5.5	1.0	6.5		
		5.0 <sup>(**)</sup>	C <sub>L</sub> = 50 pF		5.3	7.5	1.0	8.5		
t <sub>PLZ</sub> t <sub>PHZ</sub>	Output Disable Time	3.3 <sup>(*)</sup>	C <sub>L</sub> = 15 pF (***)		5.4	8.0	1.0	9.5	ns	
		3.3 <sup>(*)</sup>	C <sub>L</sub> = 50 pF (***)		7.9	11.5	1.0	13.0		
		5.0 <sup>(**)</sup>	C <sub>L</sub> = 15 pF (***)		3.6	5.0	1.0	6.0		
		5.0 <sup>(**)</sup>	C <sub>L</sub> = 50 pF (***)		5.1	7.0	1.0	8.0		
t <sub>PZL</sub> t <sub>PZH</sub>	Output Enable Time	3.3 <sup>(*)</sup>	C <sub>L</sub> = 50 pF (***)		9.5	13.0	1.0	15.0	ns	
		5.0 <sup>(**)</sup>	C <sub>L</sub> = 50 pF (***)		6.1	8.5	1.0	10.0		

(\*) Voltage range is 3.3V ± 0.3V

(\*\*) Voltage range is 5V ± 0.5V

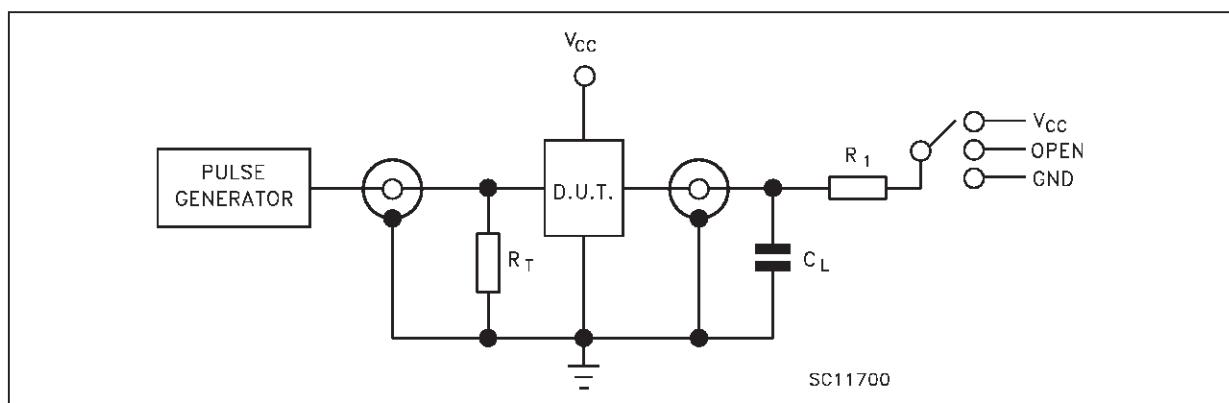
(\*\*\*) R<sub>L</sub> = 1KΩ

## CAPACITIVE CHARACTERISTICS

Symbol	Parameter	Test Conditions		Value				Unit	
		$T_A = 25^\circ\text{C}$		$-40 \text{ to } 85^\circ\text{C}$					
		Min.	Typ.	Max.	Min.	Max.			
$C_{IN}$	Input Capacitance			4				pF	
$C_{OUT}$	Output Capacitance			6	10		10	pF	
$C_{PD}$	Power Dissipation Capacitance (note 1)			14				pF	

1)  $C_{PD}$  is defined as the value of the IC's internal equivalent capacitance which is calculated from the operating current consumption without load. (Refer to Test Circuit). Average operating current can be obtained by the following equation.  $I_{CC(\text{opr})} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$

## TEST CIRCUIT



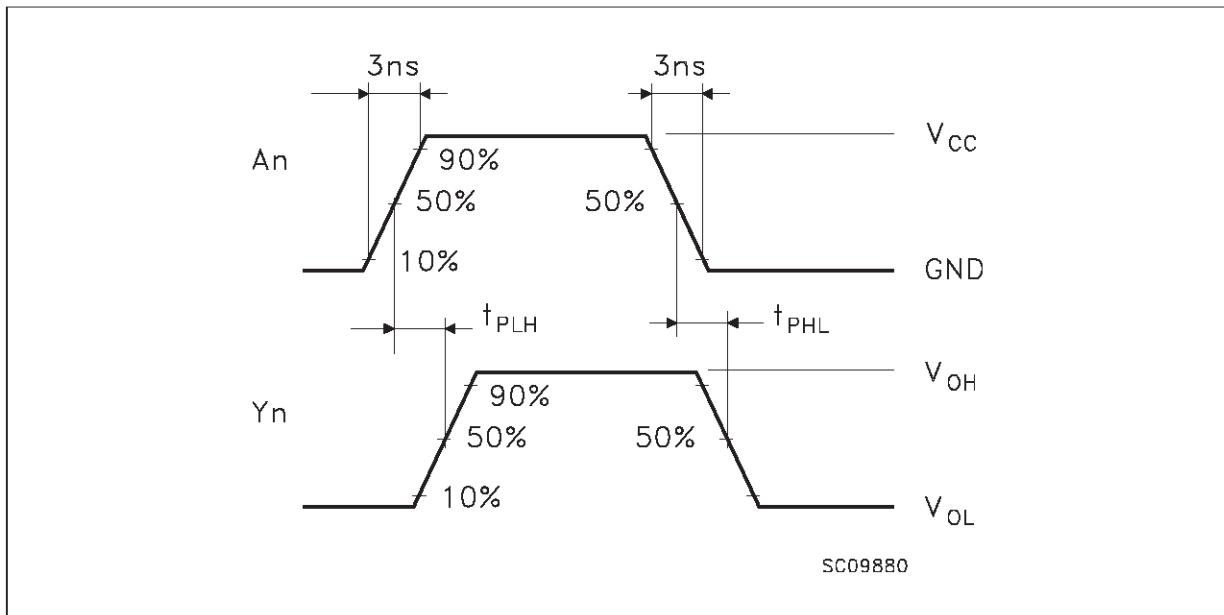
TEST	SWITCH
$t_{PLH}, t_{PHL}$	Open
$t_{PZL}, t_{PLZ}$	$V_{CC}$
$t_{PZH}, t_{PHZ}$	GND

$C_L = 15/50 \text{ pF}$  or equivalent (includes jig and probe capacitance)

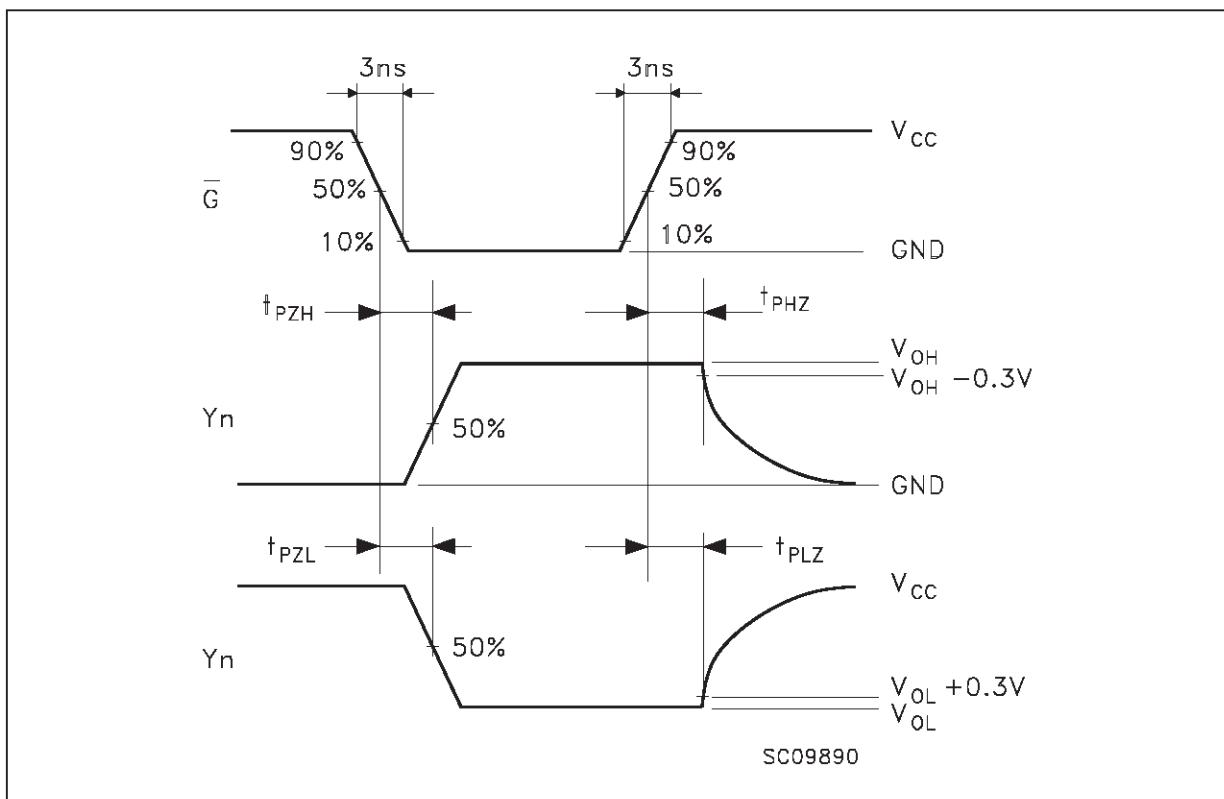
$R_L = R_1 = 1\text{K}\Omega$  or equivalent

$R_T = Z_{out}$  of pulse generator (typically  $50\Omega$ )

WAVEFORM 1: PROPAGATION DELAYS (f=1MHz; 50% duty cycle)

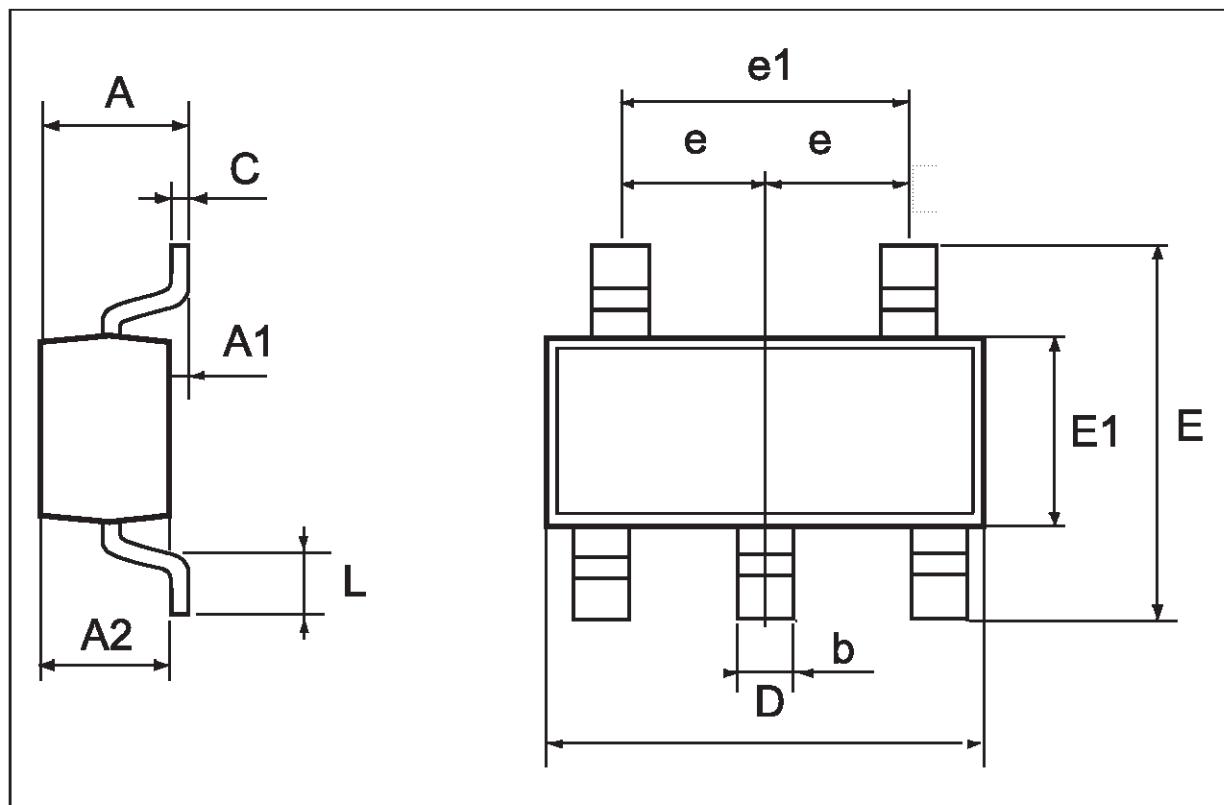


WAVEFORM 2: OUTPUT ENABLE AND DISABLE TIME (f=1MHz; 50% duty cycle)



## SOT23-5L MECHANICAL DATA

DIM.	mm			mils		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A	0.90		1.45	35.4		57.1
A1	0.00		0.15	0.0		5.9
A2	0.90		1.30	35.4		51.2
b	0.35		0.50	13.7		19.7
C	0.09		0.20	3.5		7.8
D	2.80		3.00	110.2		118.1
E	2.60		3.00	102.3		118.1
E1	1.50		1.75	59.0		68.8
L	0.35		0.55	13.7		21.6
e		0.95			37.4	
e1		1.9			74.8	



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